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Reflection, Scattering, and Diffraction from Surfaces II

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Contents

vii *Conference Committee*

SESSION 1 SCATTERING THEORY

7792 02 **The idea of the Lambertian surface: history, idealization, and system theoretical aspects and part 1 of a lost chapter on multiple reflection (Invited Paper)** [7792-01]
C. Hahlweg, B. Meißner, W. Zhao, H. Rothe, Helmut Schmidt Univ. (Germany)

7792 03 **Polar decomposition applied to light scattering by structured 2D surfaces (Invited Paper)** [7792-02]
J. M. Sanz, J. M. Saiz, F. Moreno, F. González, Univ. de Cantabria (Spain)

7792 04 **A Kirchhoff approximation for surface plasmon polaritons** [7792-03]
T. A. Leskova, A. A. Maradudin, Univ. of California, Irvine (United States)

7792 05 **Multiple scatter of vector electromagnetic waves from rough metal surfaces with infinite slopes using the Kirchhoff approximation** [7792-04]
N. C. Bruce, Univ. Nacional Autónoma de México (Mexico)

7792 06 **Nonstandard refraction of light from one- and two-dimensional dielectric quasi-periodic surfaces** [7792-05]
Z.-H. Gu, Surface Optics Corp. (United States); A. Wang, Univ. of Science and Technology of China (China)

7792 07 **Polarization of dipole scattering by randomly oriented ellipsoids** [7792-06]
S.-M. F. Nee, T.-W. Nee, National Yang-Ming Univ. (Taiwan)

SESSION 2 INSTRUMENTS AND APPLICATIONS I

7792 09 **Development of a tunable polarimetric scatterometry system in the MWIR and LWIR** [7792-08]
T. M. Fitzgerald, M. A. Marciniak, S. E. Nauyoks, Air Force Institute of Technology (United States)

7792 0A **Time depending techniques for volume and discrete boundary surface scatterometry and part II of a lost chapter in Lambert's Photometria on multiple reflection** [7792-09]
C. Hahlweg, B. Meißner, W. Zhao, H. Rothe, Helmut Schmidt Univ. (Germany)

7792 0B **Design rules for catadioptric scatterometers based on measurement requirements** [7792-10]
W. Zhao, C. Hahlweg, H. Rothe, Helmut Schmidt Univ. (Germany)

SESSION 3 OPTICAL PROPERTIES AND DIAGNOSTICS I

7792 0D **Temperature dependence of the reflectance of metals at visible wavelengths** [7792-13]
S. Maity, GE Global Research (India); A. Banerjee, Indian Institute of Science Education and Research (India); C. Mitra, GE Global Research (India)

7792 0F **Polarization/depolarization of non-diffusive anisotropic photon-scattering biomedical tissues** [7792-15]
T.-W. Nee, H.-W. Wang, S.-M. F. Nee, S. H. Wu, National Yang-Ming Univ. (Taiwan)

7792 0G **Optical measurement for the concentrations of the pickling acid with near infrared spectroscopy in steel making industry** [7792-16]
G. Kang, K. Lee, H. Park, J. Lee, Y. Jung, K. Kim, Yonsei Univ. (Korea, Republic of)

7792 0H **Bidirectional reflectance distribution of a 2D thin-film photonic crystal patterned using an atomic-force microscope** [7792-17]
N. C. Herr, M. A. Marciniak, A. G. Li, L. W. Burggraf, Air Force Institute of Technology (United States)

SESSION 4 BRDF MODELING

7792 0I **A general BRDF/BSDF model including out-of-plane dependence (Invited Paper)** [7792-18]
M. E. Thomas, R. I. Joseph, W. J. Tropf, A. M. Brown, The Johns Hopkins Univ. (United States)

7792 0J **Experimental confirmation of the Rayleigh-Rice obliquity factor** [7792-19]
J. C. Stover, The Scatter Works Inc. (United States)

7792 0K **Investigations on back scatter of typical projectiles for application of laser based trajectory measurement** [7792-20]
W. Zhao, C. Hahlweg, H. Rothe, Helmut Schmidt Univ. (Germany)

7792 0L **Restoration of scene information reflected from a non-specular surface** [7792-21]
M. G. Hoelscher, M. A. Marciniak, Air Force Institute of Technology (United States)

SESSION 5 INSTRUMENTS AND APPLICATIONS II

7792 0M **Developing a multispectral HDR imaging module for a BRDF measurement system** [7792-22]
D. B. Kim, M. K. Seo, K. Y. Kim, K. H. Lee, Gwangju Institute of Science and Technology (Korea, Republic of)

7792 0N **A stereoscopic imaging system for laser back-scatter-based trajectory measurement in ballistics** [7792-23]
E. Wilhelm, U. Chalupka, C. Hahlweg, W. Zhao, H. Rothe, Helmut Schmidt Univ. (Germany)

7792 0O **New scanning gonio-photometer for extended BRTF measurements** [7792-24]
P. Apian-Bennewitz, pab advanced technologies Ltd. (Germany)

7792 0Q **Optical inspection of flat reflective surfaces by a wave front sensor** [7792-26]
I. Lazareva, A. Nutsch, L. Pfitzner, Fraunhofer IISB (Germany); L. Frey, Fraunhofer IISB (Germany) and Friedrich-Alexander-Univ. Erlangen-Nuremberg (Germany)

7792 0R **Reflectance measurements for black absorbers made of vertically aligned carbon nanotubes** [7792-27]
X. J. Wang, O. S. Adewuyi, L. P. Wang, B. A. Cola, Z. M. Zhang, Georgia Institute of Technology (United States)

SESSION 6 COHERENCE AND SCATTERING

7792 0S **Wavelength-tunable focal length of a nanopatterned metallic planar lens with strong focusing capability (Invited Paper)** [7792-28]
L. D. Wellems, D. Huang, Air Force Research Lab. (United States); T. A. Leskova, A. A. Maradudin, Univ. of California, Irvine (United States)

7792 0T **A partially coherent slowly diffracting beam** [7792-31]
E. R. Méndez, Ctr. de Investigación Científica y de Educación Superior de Ensenada (Mexico); E. E. García-Guerrero, Univ. Autónoma de Baja California (Mexico); Z.-H. Gu, Surface Optics Corp. (United States); T. A. Leskova, A. A. Maradudin, Univ. of California, Irvine (United States)

7792 0U **Coherence effects: from spectral change to nondiffraction** [7792-29]
Z.-H. Gu, Surface Optics Corp. (United States)

SESSION 7 OPTICAL PROPERTIES AND DIAGNOSTICS II

7792 0V **Mechanical surface treatment to obtain optically cooperative surfaces vis-à-vis fringe projection** [7792-33]
O. Abo-Namous, M. Kästner, E. Reithmeier, M. Nicolaus, K. Möhwald, F.-W. Bach, Leibniz Univ. Hannover (Germany)

7792 0W **Roughness influence on periodic gratings and application to optical metrology of roughness** [7792-34]
A. Vauselle, Institut Fresnel, CNRS, Aix-Marseille Univ. (France) and STMicroelectronics (France); L. Arnaud, G. Georges, C. Amra, C. Deumié, Institut Fresnel, CNRS, Aix-Marseille Univ. (France); P. Maillot, STMicroelectronics (France)

7792 0X **PASCAL: instrument for accurate precise characterization of Lambertian materials** [7792-35]
V. Murgai, J. M. Nixt, E. M. Moskun, C. M. Jones, C. E. Payton, J. D. CdeBaca, Raytheon Space & Airborne Systems (United States)

7792 0Y **A model for the optical properties of amorphous carbon (soot)** [7792-36]
M. E. Thomas, D. E. Freund, R. I. Joseph, The Johns Hopkins Univ. (United States)

SESSION 8 OPTICAL PROPERTIES AND DIAGNOSTICS III

7792 0Z **Preliminary characterization study of a gold-coated concentrator for hemispherical longwave irradiance measurements** [7792-37]
J. Zeng, Utah State Univ. (United States); L. Hanssen, National Institute of Standards and Technology (United States); I. Reda, National Renewable Energy Lab. (United States); J. Scheuch, Labsphere, Inc. (United States)

7792 10 **Stress measurement of thin wafer using reflection grating method** [7792-38]
C. S. Ng, Nanyang Technological Univ. (Singapore) and Infineon Technologies Malaysia Sdn Bhd. (Malaysia); A. K. Asundi, Nanyang Technological Univ. (Singapore)

7792 11 **Optical material characterization through BSDF measurement and analysis** [7792-39]
A. M. Brown, D. V. Hahn, M. E. Thomas, D. M. Brown, J. Makowski, The Johns Hopkins Univ. (United States)

POSTER SESSION

7792 13 **Effective decomposition of pearlescent paints** [7792-32]
M. K. Seo, D. B. Kim, K. Y. Kim, K. H. Lee, Gwangju Institute of Science and Technology (Korea, Republic of)

7792 15 **Improvements of nanometer particle's measuring system based on photon correlation spectroscopy** [7792-42]
S. Deng, Q. Zhang, J. Xia, Y. Xiong, S. Guo, Y. Yang, National Univ. of Defense Technology (China)

7792 19 **A novel method for diameter estimation of small opaque objects using Fraunhofer diffraction** [7792-47]
K. Vyas, K. R. Lolla, Indian Institute of Science (India)

7792 1A **Topography measurement of specular and diffuse surfaces** [7792-48]
D. I. Serrano García, A. Martínez García, J. A. Rayas-Alvarez, Ctr. de Investigaciones en Óptica, A.C. (Mexico)

Author Index

Conference Committee

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1 Scattering Theory
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2 Instruments and Applications I
Soe-Mie F. Nee, National Yang-Ming University (Taiwan)

3 Optical Properties and Diagnostics I
Neil C. Bruce, Universidad Nacional Autónoma de México (Mexico)

4 BRDF Modeling
Michael E. Thomas, The Johns Hopkins University (United States)

5 Instruments and Applications II
Hendrik Rothe, Helmut Schmidt University (Germany)

6 Coherence and Scattering
Danhong Huang, Air Force Research Laboratory (United States)

7 Optical Properties and Diagnostics II
Hsueh Mei Graham, Lockheed Martin Corporation (United States)

8 Optical Properties and Diagnostics III
Soe-Mie F. Nee, National Yang-Ming University (Taiwan)